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# **Fundamentals of Manufacturing**

"Reducing Cost of Manufacturing Lifecycle Through Understanding the Value Of Test"

## June 19, 2001

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## **Duane Lowenstein**



- Manager of America's Strategic
  Business Development Organization
- 20 years experience in manufacturing
- Professional positions include Production/Manufacturing Manager, New Product Introduction Manager
- BS degree in Mechanical Engineering from Rutgers University
- MBA from Penn State University

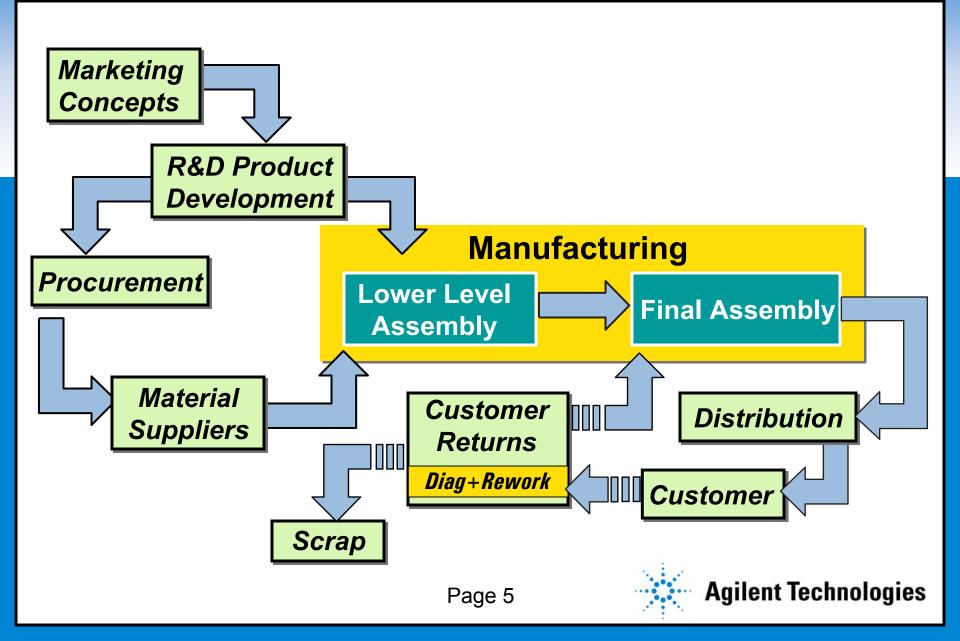


- 1. Understanding the value of test as an inspection process step within the manufacturing lifecycle.
- 2. Map different test strategies to different phases of the manufacturing lifecycle and be able to identify mismatches:
- 3. Articulate how cost tradeoffs effect manufacturing processes and enterprise business results;
- 4. The role test plays in achieving manufacturing performance improvement.

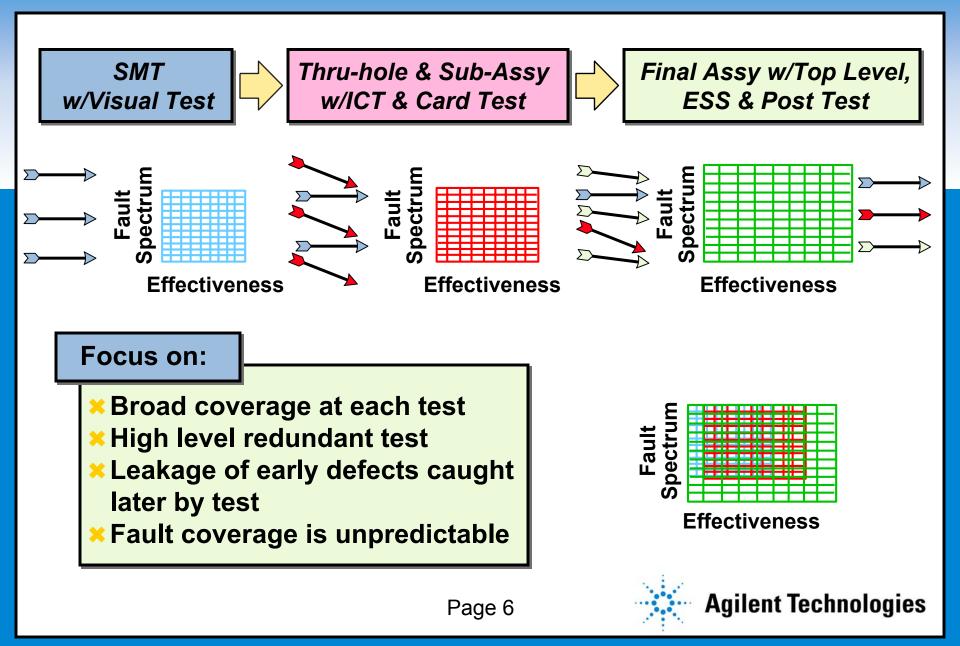


- Brief review of key electronic manufacturing parameters
- Test and cost drivers
- Using test to improve performance
- Sorting through the complexity
- The impact of TTM
- Case study example
- Summary / resources / Q&A

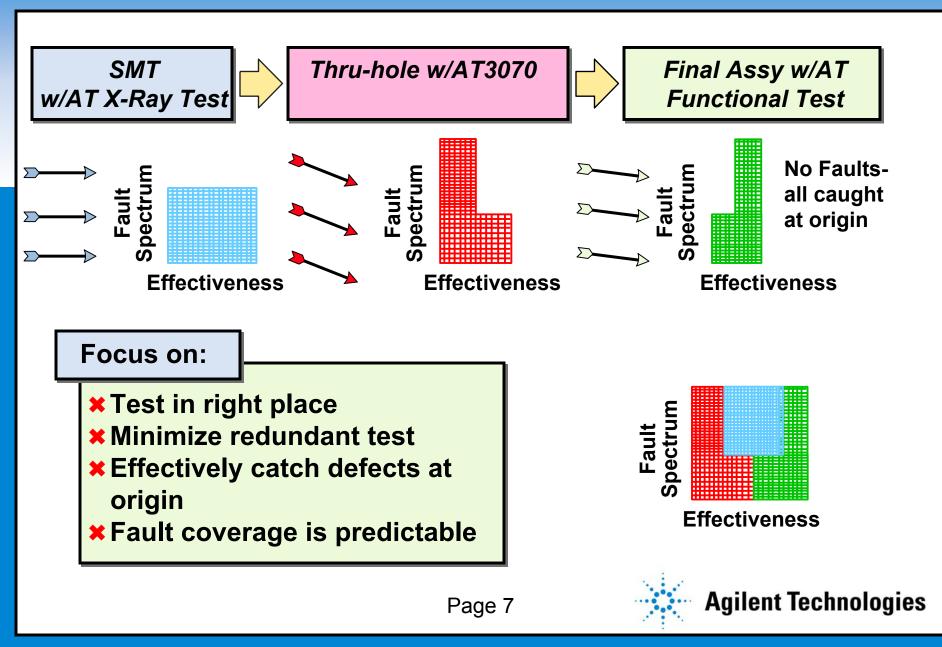
# **Simplified Systems View of Business**



# **Standard Test Strategy**



# **Optimized Test Strategy**



# **Test and Cost Drivers**

#### **Product Eng.**

Manufacturing

**Warranty** 

#### **Functions**

- Prototypes per year
- Turns per prototype
- Time to develop test
- Time to market without test
- Component types
- Interconnect technology
- Re-occurring test costs

#### **Cost Factors**

- # Prototype test fixtures
- Delay to test product due to debug of test
- Delay of product to market because of test
- Delay due to test gaps



# **Test and Cost Drivers**

**Product Eng.** 

Manufacturing

Warranty

## **Functions**

- Time to test
- Time to diagnose
- Time to repair
- Test coverage
- Cycle time between cause and test detection
- Time to get process in control Prototypes per year

## **Cost Factors**

- Time to test
- Cost of visual inspection
- Defects caught at functional test
- Cost of diagnostics and repair
- Process not in control
- Cost of 'bone pile'



# **Test and Cost Drivers**

## Product Eng.

Manufacturing

### **Functions**

- # returns
- Time to diagnose
- # of returns due to manufacturing defects
- # of returns due to design defects

#### **Cost Factors**

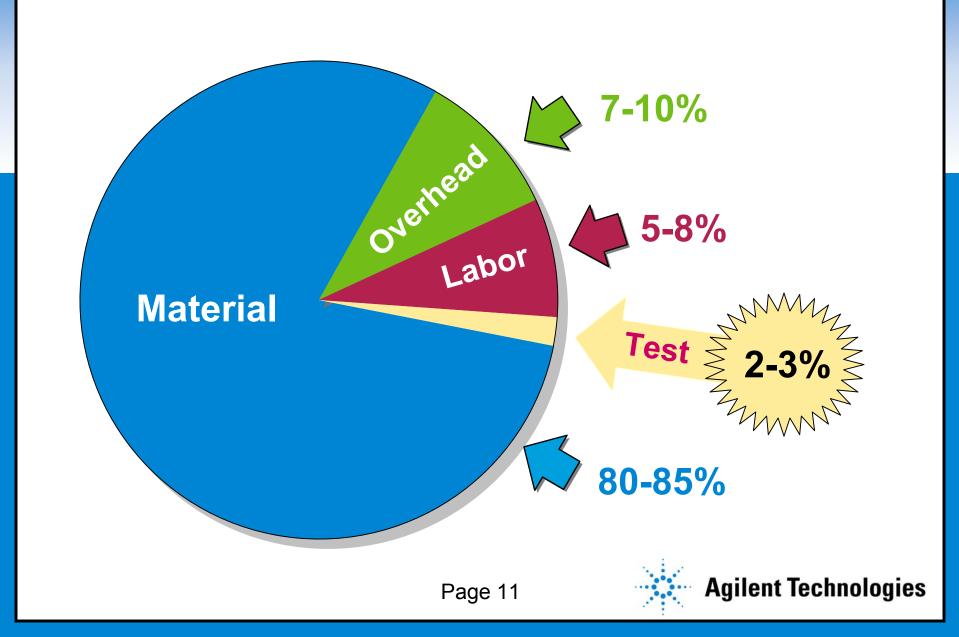
- Good will cost
- Replacement cost
- Cost of diagnostics
- Cost of same design defect in next product



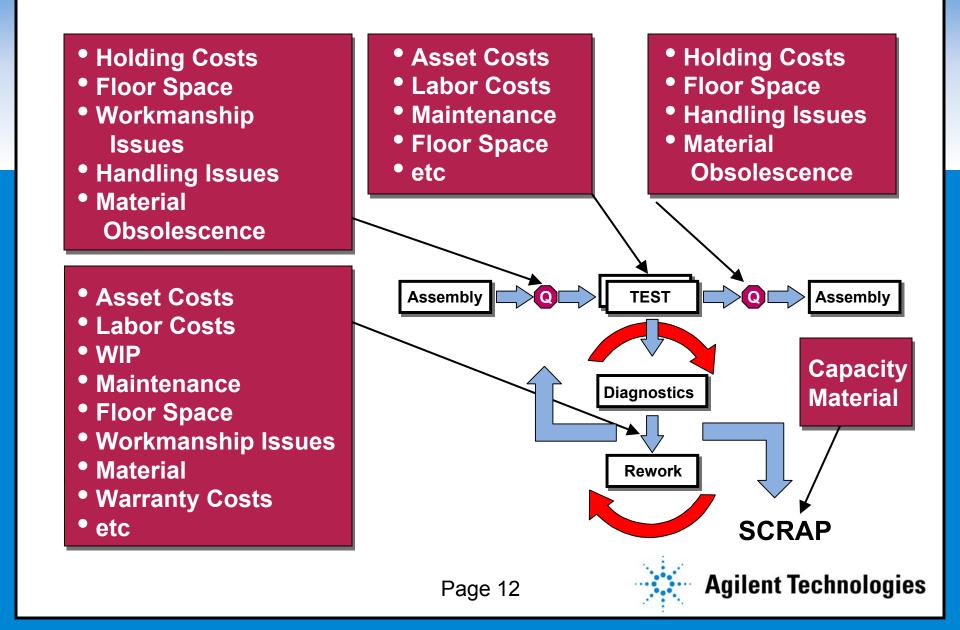


Warranty

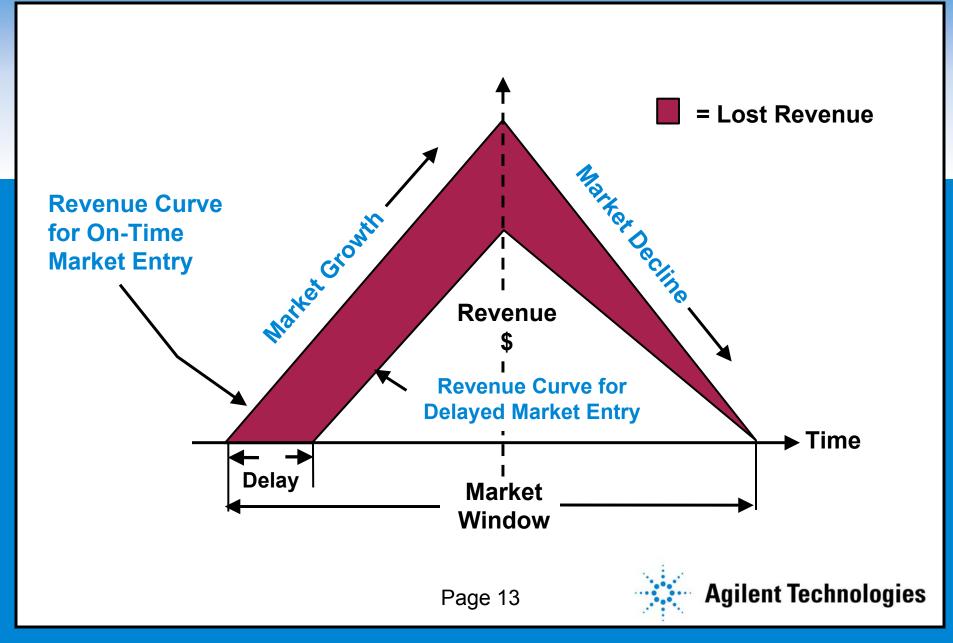
## What Does it Cost to Build a Product?



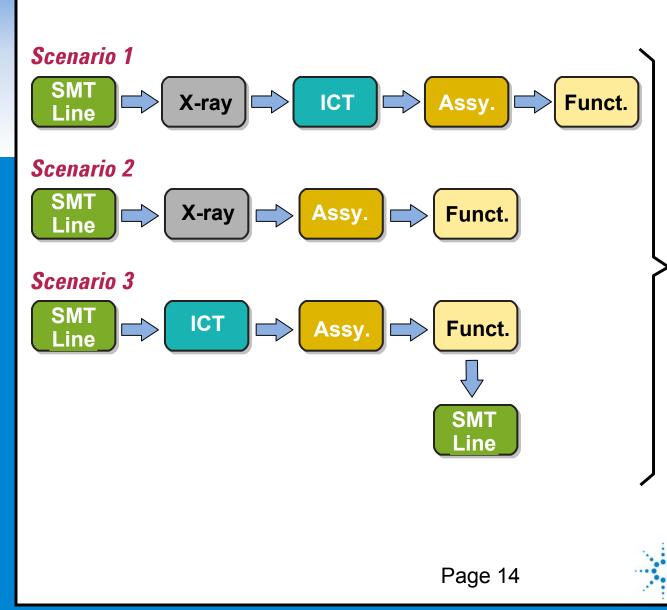
## How Test Impacts Manufacturing Costs



# The Impact of TTM



# **Sorting Through Test Complexity**



#### **Business Considerations**

- Cost, Markets, Growth Technology
- Product Life Cycle
- Design
- Inventory/WIP
- Volume
- Production Rate
- Globalization
- Return Rate
- Components
- Complexity
- Utilization
- Fault Coverage
- Quality, Yield, SPC

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Resources, Outsourcing

etc.....

# Let's Look at an Example

## Situation:

- 7,000 Boards/Per Month
- Cycle Time = 10 Days
- WIP = 12,500 Boards
- Overall Pristine Yield = 74%
- Lower Level Assy. Includes SMT & Thru-hole Processes w/ Environmental Stress Test of 6 Hours/22 Cycles, 82% ICT Yield
- Final Assembly includes two Functional Tests w/94% & 97% Yield, respectively
- Customer returns = .2%





# Let's Look at an Example - continued -

## **Lower Level Assembly**

#### Areas of Concern

## Solution Set

- High number of solder-related defects
- High levels of WIP (9000 boards)
- Long delay time between board assembly and test
- High levels of material failures
- Failures can not be traced back to root cause

- Implement a test solution that has the highest effectiveness in solder related defects (X-Ray)
- Remove areas of WIP by re-aligning layout
- Develop Root Cause analysis process including material failures



# Let's Look at an Example - continued -

## **Final Assembly**

## Areas of Concern

## Solution Set

- High levels of WIP (3,500 boards)
- Long delay times between assembly and test
- High levels of material failures
- Long diagnostic times (2 hours average)

- Remove areas of WIP by re-aligning layout
- Implement process for real time feedback linked with diagnostic and repair process
- Develop Root Cause analysis process including material failures
- Implemented automated diagnostic software



# Let's Look at an Example - continued -

## **Financial Impact**

- Diagnostic and repair savings from more effective test
- Elimination of scrapping good material
- Elimination of warranty returns from more effective test
- 15% more capacity and reduction in WIP because of improved yields
- Double the through-put and elimination of redundant test processes







# **Key Concepts**

Primary test parameters are:

- Effectiveness Fault Spectrum
- The effects of test vary based on the manufacturing environment (volume, quality, time) and function (R&D, production manufacturing, warranty).
- Typical manufacturing costs are:
  - 80-85% material, 7-10% overhead, 5-8% labor, 2-3% test
- An optimized test strategy can yield financial performance improvement in the following areas:
  - lower diagnostic & repair costs
  - warranty returns reduced or eliminated
  - reduced scrap

- increased plant capacity

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- increased throughput



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